

Notice of References Cited

Application/Control No.

09/998,131

Applicant(s)/Patent Under
Reexamination
PARK ET AL.

Examiner

Belur V Keshavan

Art Unit

2825

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,025,254	02-2000	Doyle et al.	438/592
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Broadbent et al., Application Of Self-Aligned CoSi2 interconnection in Submicrometer CMOS Transistors, IEEE Transaction On Electron Devices, pp 2440-2446, 11/1989
	V	
	W	
	X	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.